

<b>Notice of References Cited</b>	Application/Control No. 10/530,759	Applicant(s)/Patent Under Reexamination LEPPANEN ET AL.	
	Examiner JASON RECEK	Art Unit 2442	Page 1 of 1

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*	C	US-2006/0195565 A1	08-2006	De-Poorter, Antoine	709/224
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**NON-PATENT DOCUMENTS**

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